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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Obsolete
Core Processor	C166SV2
Core Size	16/32-Bit
Speed	80MHz
Connectivity	CANbus, EBI/EMI, I ² C, LINbus, SPI, SSC, UART/USART, USI
Peripherals	I ² S, POR, PWM, WDT
Number of I/O	75
Program Memory Size	832KB (832K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	50K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 5.5V
Data Converters	A/D 16x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP Exposed Pad
Supplier Device Package	PG-LQFP-100-8
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/xc2365a104f80laakxuma1

Summary of Features

- Two Synchronizable A/D Converters with a total of up to 16 channels, 10-bit resolution, conversion time below 1 μ s, optional data preprocessing (data reduction, range check), broken wire detection
- Up to 6 serial interface channels to be used as UART, LIN, high-speed synchronous channel (SPI), IIC bus interface (10-bit addressing, 400 kbit/s), IIS interface
- On-chip MultiCAN interface (Rev. 2.0B active) with up to 64 message objects (Full CAN/Basic CAN) on up to 3 CAN nodes and gateway functionality
- On-chip system timer and on-chip real time clock
- Up to 12 Mbytes external address space for code and data
 - Programmable external bus characteristics for different address ranges
 - Multiplexed or demultiplexed external address/data buses
 - Selectable address bus width
 - 16-bit or 8-bit data bus width
 - Four programmable chip-select signals
- Single power supply from 3.0 V to 5.5 V
- Programmable watchdog timer and oscillator watchdog
- Up to 76 general purpose I/O lines
- On-chip bootstrap loaders
- Supported by a full range of development tools including C compilers, macro-assembler packages, emulators, evaluation boards, HLL debuggers, simulators, logic analyzer disassemblers, programming boards
- On-chip debug support via Device Access Port (DAP) or JTAG interface
- 100-pin Green LQFP package, 0.5 mm (19.7 mil) pitch

Table 6 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
30	P5.8	I	In/A	Bit 8 of Port 5, General Purpose Input
	ADC0_CH8	I	In/A	Analog Input Channel 8 for ADC0
	ADC1_CH8	I	In/A	Analog Input Channel 8 for ADC1
	CCU6x_T12H RC	I	In/A	External Run Control Input for T12 of CCU60/1
	CCU6x_T13H RC	I	In/A	External Run Control Input for T13 of CCU60/1
	U2C0_DX0F	I	In/A	USIC2 Channel 0 Shift Data Input
31	P5.9	I	In/A	Bit 9 of Port 5, General Purpose Input
	ADC0_CH9	I	In/A	Analog Input Channel 9 for ADC0
	ADC1_CH9	I	In/A	Analog Input Channel 9 for ADC1
	CC2_T7IN	I	In/A	CAPCOM2 Timer T7 Count Input
32	P5.10	I	In/A	Bit 10 of Port 5, General Purpose Input
	ADC0_CH10	I	In/A	Analog Input Channel 10 for ADC0
	ADC1_CH10	I	In/A	Analog Input Channel 10 for ADC1
	BRKIN_A	I	In/A	OCDS Break Signal Input
	U2C1_DX0F	I	In/A	USIC2 Channel 1 Shift Data Input
	CCU61_T13 HRA	I	In/A	External Run Control Input for T13 of CCU61
33	P5.11	I	In/A	Bit 11 of Port 5, General Purpose Input
	ADC0_CH11	I	In/A	Analog Input Channel 11 for ADC0
	ADC1_CH11	I	In/A	Analog Input Channel 11 for ADC1
34	P5.13	I	In/A	Bit 13 of Port 5, General Purpose Input
	ADC0_CH13	I	In/A	Analog Input Channel 13 for ADC0
35	P5.15	I	In/A	Bit 15 of Port 5, General Purpose Input
	ADC0_CH15	I	In/A	Analog Input Channel 15 for ADC0
	RxDC2F	I	In/A	CAN Node 2 Receive Data Input

Table 6 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
36	P2.12	O0 / I	St/B	Bit 12 of Port 2, General Purpose Input/Output
	U0C0_SELO4	O1	St/B	USIC0 Channel 0 Select/Control 4 Output
	U0C1_SELO3	O2	St/B	USIC0 Channel 1 Select/Control 3 Output
	TXDC2	O3	St/B	CAN Node 2 Transmit Data Output
	READY	IH	St/B	External Bus Interface READY Input
37	P2.11	O0 / I	St/B	Bit 11 of Port 2, General Purpose Input/Output
	U0C0_SELO2	O1	St/B	USIC0 Channel 0 Select/Control 2 Output
	U0C1_SELO2	O2	St/B	USIC0 Channel 1 Select/Control 2 Output
	$\overline{\text{BHE}}/\overline{\text{WRH}}$	OH	St/B	External Bus Interf. High-Byte Control Output Can operate either as Byte High Enable ($\overline{\text{BHE}}$) or as Write strobe for High Byte ($\overline{\text{WRH}}$).
39	P2.0	O0 / I	St/B	Bit 0 of Port 2, General Purpose Input/Output
	AD13	OH / IH	St/B	External Bus Interface Address/Data Line 13
	RxDC0C	I	St/B	CAN Node 0 Receive Data Input
	T5INB	I	St/B	GPT12E Timer T5 Count/Gate Input
40	P2.1	O0 / I	St/B	Bit 1 of Port 2, General Purpose Input/Output
	TxDC0	O1	St/B	CAN Node 0 Transmit Data Output
	AD14	OH / IH	St/B	External Bus Interface Address/Data Line 14
	T5EUDB	I	St/B	GPT12E Timer T5 External Up/Down Control Input
	ESR1_5	I	St/B	ESR1 Trigger Input 5
41	P2.2	O0 / I	St/B	Bit 2 of Port 2, General Purpose Input/Output
	TxDC1	O1	St/B	CAN Node 1 Transmit Data Output
	AD15	OH / IH	St/B	External Bus Interface Address/Data Line 15
	ESR2_5	I	St/B	ESR2 Trigger Input 5

Table 6 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
62	P10.2	O0 / I	St/B	Bit 2 of Port 10, General Purpose Input/Output
	U0C0_SCLK OUT	O1	St/B	USIC0 Channel 0 Shift Clock Output
	CCU60_CC6 2	O2	St/B	CCU60 Channel 2 Output
	AD2	OH / IH	St/B	External Bus Interface Address/Data Line 2
	CCU60_CC6 2INA	I	St/B	CCU60 Channel 2 Input
	U0C0_DX1B	I	St/B	USIC0 Channel 0 Shift Clock Input
63	P0.4	O0 / I	St/B	Bit 4 of Port 0, General Purpose Input/Output
	U1C1_SELO 0	O1	St/B	USIC1 Channel 1 Select/Control 0 Output
	U1C0_SELO 1	O2	St/B	USIC1 Channel 0 Select/Control 1 Output
	CCU61_COUT61	O3	St/B	CCU61 Channel 1 Output
	A4	OH	St/B	External Bus Interface Address Line 4
	U1C1_DX2A	I	St/B	USIC1 Channel 1 Shift Control Input
	RxDC1B	I	St/B	CAN Node 1 Receive Data Input
	ESR2_8	I	St/B	ESR2 Trigger Input 8
65	P2.13	O0 / I	St/B	Bit 13 of Port 2, General Purpose Input/Output
	U2C1_SELO 2	O1	St/B	USIC2 Channel 1 Select/Control 2 Output
	RxDC2D	I	St/B	CAN Node 2 Receive Data Input
66	P2.10	O0 / I	St/B	Bit 10 of Port 2, General Purpose Input/Output
	U0C1_DOUT	O1	St/B	USIC0 Channel 1 Shift Data Output
	U0C0_SELO 3	O2	St/B	USIC0 Channel 0 Select/Control 3 Output
	CC2_CC23	O3 / I	St/B	CAPCOM2 CC23IO Capture Inp./ Compare Out.
	A23	OH	St/B	External Bus Interface Address Line 23
	U0C1_DX0E	I	St/B	USIC0 Channel 1 Shift Data Input
	CAPINA	I	St/B	GPT12E Register CAPREL Capture Input

General Device Information

Table 6 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
79	P10.8	O0 / I	St/B	Bit 8 of Port 10, General Purpose Input/Output
	U0C0_MCLK OUT	O1	St/B	USIC0 Channel 0 Master Clock Output
	U0C1_SELO 0	O2	St/B	USIC0 Channel 1 Select/Control 0 Output
	U2C1_DOUT	O3	St/B	USIC2 Channel 1 Shift Data Output
	AD8	OH / IH	St/B	External Bus Interface Address/Data Line 8
	CCU60_CCP OS1A	I	St/B	CCU60 Position Input 1
	U0C0_DX1C	I	St/B	USIC0 Channel 0 Shift Clock Input
	BRKIN_B	I	St/B	OCDS Break Signal Input
80	T3EUDB	I	St/B	GPT12E Timer T3 External Up/Down Control Input
	P10.9	O0 / I	St/B	Bit 9 of Port 10, General Purpose Input/Output
	U0C0_SELO 4	O1	St/B	USIC0 Channel 0 Select/Control 4 Output
	U0C1_MCLK OUT	O2	St/B	USIC0 Channel 1 Master Clock Output
	AD9	OH / IH	St/B	External Bus Interface Address/Data Line 9
	CCU60_CCP OS2A	I	St/B	CCU60 Position Input 2
	TCK_B	I/H	St/B	DAP0/JTAG Clock Input If JTAG pos. B is selected during start-up, an internal pull-up device will hold this pin high when nothing is driving it. If DAP pos. 1 is selected during start-up, an internal pull-down device will hold this pin low when nothing is driving it.
	T3INB	I	St/B	GPT12E Timer T3 Count/Gate Input

Table 6 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
81	P1.1	O0 / I	St/B	Bit 1 of Port 1, General Purpose Input/Output
	U1C0_SELO5	O2	St/B	USIC1 Channel 0 Select/Control 5 Output
	U2C1_DOUT	O3	St/B	USIC2 Channel 1 Shift Data Output
	A9	OH	St/B	External Bus Interface Address Line 9
	ESR2_3	I	St/B	ESR2 Trigger Input 3
	U2C1_DX0C	I	St/B	USIC2 Channel 1 Shift Data Input
82	P10.10	O0 / I	St/B	Bit 10 of Port 10, General Purpose Input/Output
	U0C0_SELO0	O1	St/B	USIC0 Channel 0 Select/Control 0 Output
	CCU60_COUT63	O2	St/B	CCU60 Channel 3 Output
	AD10	OH / IH	St/B	External Bus Interface Address/Data Line 10
	U0C0_DX2C	I	St/B	USIC0 Channel 0 Shift Control Input
	U0C1_DX1A	I	St/B	USIC0 Channel 1 Shift Clock Input
	TDI_B	IH	St/B	JTAG Test Data Input If JTAG pos. B is selected during start-up, an internal pull-up device will hold this pin high when nothing is driving it.
83	P10.11	O0 / I	St/B	Bit 11 of Port 10, General Purpose Input/Output
	U1C0_SCLKOUT	O1	St/B	USIC1 Channel 0 Shift Clock Output
	BRKOUT	O2	St/B	OCDS Break Signal Output
	AD11	OH / IH	St/B	External Bus Interface Address/Data Line 11
	U1C0_DX1D	I	St/B	USIC1 Channel 0 Shift Clock Input
	RxDC2B	I	St/B	CAN Node 2 Receive Data Input
	TMS_B	IH	St/B	JTAG Test Mode Selection Input If JTAG pos. B is selected during start-up, an internal pull-up device will hold this pin high when nothing is driving it.

Table 6 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
84	P1.2	O0 / I	St/B	Bit 2 of Port 1, General Purpose Input/Output
	U1C0_SELO6	O2	St/B	USIC1 Channel 0 Select/Control 6 Output
	U2C1_SCLKOUT	O3	St/B	USIC2 Channel 1 Shift Clock Output
	A10	OH	St/B	External Bus Interface Address Line 10
	ESR1_4	I	St/B	ESR1 Trigger Input 4
	CCU61_T12HRB	I	St/B	External Run Control Input for T12 of CCU61
	U2C1_DX0D	I	St/B	USIC2 Channel 1 Shift Data Input
	U2C1_DX1C	I	St/B	USIC2 Channel 1 Shift Clock Input
85	P10.12	O0 / I	St/B	Bit 12 of Port 10, General Purpose Input/Output
	U1C0_DOUT	O1	St/B	USIC1 Channel 0 Shift Data Output
	TxDC2	O2	St/B	CAN Node 2 Transmit Data Output
	TDO_B	OH / IH	St/B	JTAG Test Data Output / DAP1 Input/Output If DAP pos. 1 is selected during start-up, an internal pull-down device will hold this pin low when nothing is driving it.
	AD12	OH / IH	St/B	External Bus Interface Address/Data Line 12
	U1C0_DX0C	I	St/B	USIC1 Channel 0 Shift Data Input
	U1C0_DX1E	I	St/B	USIC1 Channel 0 Shift Clock Input
86	P10.13	O0 / I	St/B	Bit 13 of Port 10, General Purpose Input/Output
	U1C0_DOUT	O1	St/B	USIC1 Channel 0 Shift Data Output
	U1C0_SELO3	O3	St/B	USIC1 Channel 0 Select/Control 3 Output
	WR/WRL	OH	St/B	External Bus Interface Write Strobe Output Active for each external write access, when $\overline{\text{WR}}$, active for ext. writes to the low byte, when $\overline{\text{WRL}}$.
	U1C0_DX0D	I	St/B	USIC1 Channel 0 Shift Data Input

General Device Information

Table 6 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
98	ESR1	O0 / I	St/B	External Service Request 1 After power-up, an internal weak pull-up device holds this pin high when nothing is driving it.
	RxDC0E	I	St/B	CAN Node 0 Receive Data Input
	U1C0_DX0F	I	St/B	USIC1 Channel 0 Shift Data Input
	U1C0_DX2C	I	St/B	USIC1 Channel 0 Shift Control Input
	U1C1_DX0C	I	St/B	USIC1 Channel 1 Shift Data Input
	U1C1_DX2B	I	St/B	USIC1 Channel 1 Shift Control Input
	U2C1_DX2C	I	St/B	USIC2 Channel 1 Shift Control Input
99	ESR0	O0 / I	St/B	External Service Request 0 After power-up, ESR0 operates as open-drain bidirectional reset with a weak pull-up.
	U1C0_DX0E	I	St/B	USIC1 Channel 0 Shift Data Input
	U1C0_DX2B	I	St/B	USIC1 Channel 0 Shift Control Input
10	V_{DDIM}	-	PS/M	Digital Core Supply Voltage for Domain M Decouple with a ceramic capacitor, see Data Sheet for details.
38, 64, 88	V_{DDI1}	-	PS/1	Digital Core Supply Voltage for Domain 1 Decouple with a ceramic capacitor, see Data Sheet for details. All V_{DDI1} pins must be connected to each other.
14	V_{DDPA}	-	PS/A	Digital Pad Supply Voltage for Domain A Connect decoupling capacitors to adjacent V_{DDP}/V_{SS} pin pairs as close as possible to the pins. <i>Note: The A/D Converters and ports P5, P6 and P15 are fed from supply voltage V_{DDPA}.</i>

Functional Description

Table 9 Compare Modes (cont'd)

Compare Modes	Function
Mode 2	Interrupt-only compare mode; Only one compare interrupt per timer period is generated
Mode 3	Pin set '1' on match; pin reset '0' on compare timer overflow; Only one compare event per timer period is generated
Double Register Mode	Two registers operate on one pin; Pin toggles on each compare match; Several compare events per timer period are possible
Single Event Mode	Generates single edges or pulses; Can be used with any compare mode

3.9 Capture/Compare Units CCU6x

The XC236xA types feature the CCU60, CCU61 unit(s).

The CCU6 is a high-resolution capture and compare unit with application-specific modes. It provides inputs to start the timers synchronously, an important feature in devices with several CCU6 modules.

The module provides two independent timers (T12, T13), that can be used for PWM generation, especially for AC motor control. Additionally, special control modes for block commutation and multi-phase machines are supported.

Timer 12 Features

- Three capture/compare channels, where each channel can be used either as a capture or as a compare channel.
- Supports generation of a three-phase PWM (six outputs, individual signals for high-side and low-side switches)
- 16-bit resolution, maximum count frequency = peripheral clock
- Dead-time control for each channel to avoid short circuits in the power stage
- Concurrent update of the required T12/13 registers
- Center-aligned and edge-aligned PWM can be generated
- Single-shot mode supported
- Many interrupt request sources
- Hysteresis-like control mode
- Automatic start on a HW event (T12HR, for synchronization purposes)

Timer 13 Features

- One independent compare channel with one output
- 16-bit resolution, maximum count frequency = peripheral clock
- Can be synchronized to T12
- Interrupt generation at period match and compare match
- Single-shot mode supported
- Automatic start on a HW event (T13HR, for synchronization purposes)

Additional Features

- Block commutation for brushless DC drives implemented
- Position detection via Hall sensor pattern
- Automatic rotational speed measurement for block commutation
- Integrated error handling
- Fast emergency stop without CPU load via external signal ($\overline{\text{CTRAP}}$)
- Control modes for multi-channel AC drives
- Output levels can be selected and adapted to the power stage

4 Electrical Parameters

The operating range for the XC236xA is defined by its electrical parameters. For proper operation the specified limits must be respected when integrating the device in its target environment.

4.1 General Parameters

These parameters are valid for all subsequent descriptions, unless otherwise noted.

4.1.1 Absolut Maximum Rating Conditions

Stresses above the values listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only. Functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for an extended time may affect device reliability.

During absolute maximum rating overload conditions ($V_{IN} > V_{DDP}$ or $V_{IN} < V_{SS}$) the voltage on V_{DDP} pins with respect to ground (V_{SS}) must not exceed the values defined by the absolute maximum ratings.

Table 12 Absolute Maximum Rating Parameters

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Output current on a pin when high value is driven	I_{OH} SR	-30	—	—	mA	
Output current on a pin when low value is driven	I_{OL} SR	—	—	30	mA	
Overload current	I_{OV} SR	-10	—	10	mA	¹⁾
Absolute sum of overload currents	$\Sigma I_{OV} $ SR	—	—	100	mA	¹⁾
Junction Temperature	T_J SR	-40	—	150	°C	
Storage Temperature	T_{ST} SR	-65	—	150	°C	
Digital supply voltage for IO pads and voltage regulators	V_{DDPA}, V_{DDPB} SR	-0.5	—	6.0	V	
Voltage on any pin with respect to ground (V_{SS})	V_{IN} SR	-0.5	—	$V_{DDP} + 0.5$	V	$V_{IN} \leq V_{DDP(max)}$

¹⁾ Overload condition occurs if the input voltage V_{IN} is out of the absolute maximum rating range. In this case the current must be limited to the listed values by design measures.

Electrical Parameters

Table 13 Operating Conditions (cont'd)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Absolute sum of overload currents	$\Sigma I_{OV} $ SR	—	—	50	mA	not subject to production test
Digital core supply voltage for domain M ⁸⁾	V_{DDIM} CC	—	1.5	—		
Digital core supply voltage for domain 1 ⁸⁾	V_{DDI1} CC	—	1.5	—		
Digital supply voltage for IO pads and voltage regulators	V_{DDP} SR	4.5	—	5.5	V	
Digital ground voltage	V_{SS} SR	—	0	—	V	

- 1) To ensure the stability of the voltage regulators the EVRs must be buffered with ceramic capacitors. Separate buffer capacitors with the recommended values shall be connected as close as possible to each V_{DDIM} and V_{DDI1} pin to keep the resistance of the board tracks below 2 Ohm. Connect all V_{DDI1} pins together. The minimum capacitance value is required for proper operation under all conditions (e.g. temperature). Higher values slightly increase the startup time.
- 2) Use one Capacitor for each pin.
- 3) This is the reference load. For bigger capacitive loads, use the derating factors listed in the PAD properties section.
- 4) The timing is valid for pin drivers operating in default current mode (selected after reset). Reducing the output current may lead to increased delays or reduced driving capability (C_L).
- 5) The operating frequency range may be reduced for specific device types. This is indicated in the device designation (...FxxL). 80 MHz devices are marked ...F80L.
- 6) Overload conditions occur if the standard operating conditions are exceeded, i.e. the voltage on any pin exceeds the specified range: $V_{OV} > V_{IHmax}$ ($I_{OV} > 0$) or $V_{OV} < V_{ILmin}$ ($I_{OV} < 0$). The absolute sum of input overload currents on all pins may not exceed 50 mA. The supply voltages must remain within the specified limits. Proper operation under overload conditions depends on the application. Overload conditions must not occur on pin XTAL1 (powered by V_{DDIM}).
- 7) An overload current (I_{OV}) through a pin injects a certain error current (I_{INj}) into the adjacent pins. This error current adds to the respective pins leakage current (I_{OZ}). The amount of error current depends on the overload current and is defined by the overload coupling factor K_{OV} . The polarity of the injected error current is inverse compared to the polarity of the overload current that produces it. The total current through a pin is $|I_{TOT}| = |I_{OZ}| + (|I_{OV}| \cdot K_{OV})$. The additional error current may distort the input voltage on analog inputs.
- 8) Value is controlled by on-chip regulator

4.2.2 DC Parameters for Lower Voltage Area

Keeping signal levels within the limits specified in this table ensures operation without overload conditions. For signal levels outside these specifications, also refer to the specification of the overload current I_{OV} .

Note: Operating Conditions apply.

Table 15 is valid under the following conditions:

$V_{DDP} \geq 3.0 \text{ V}$; $V_{DDPtyp} = 3.3 \text{ V}$; $V_{DDP} \leq 4.5 \text{ V}$

Table 15 DC Characteristics for Lower Voltage Range

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Pin capacitance (digital inputs/outputs). To be doubled for double bond pins. ¹⁾	$C_{IO} \text{ CC}$	–	–	10	pF	not subject to production test
Input Hysteresis ²⁾	$HYS \text{ CC}$	$0.07 \times V_{DDP}$	–	–	V	$R_S = 0 \text{ Ohm}$
Absolute input leakage current on pins of analog ports ³⁾	$ I_{OZ1} \text{ CC}$	–	10	200	nA	$V_{IN} > V_{SS}$; $V_{IN} < V_{DDP}$
Absolute input leakage current for all other pins. To be doubled for double bond pins. ³⁾¹⁾⁴⁾	$ I_{OZ2} \text{ CC}$	–	0.2	2.5	μA	$T_J \leq 110 \text{ }^\circ\text{C}$; $V_{IN} < V_{DDP}$; $V_{IN} > V_{SS}$
		–	0.2	8	μA	$T_J \leq 150 \text{ }^\circ\text{C}$; $V_{IN} < V_{DDP}$; $V_{IN} > V_{SS}$
Pull Level Force Current ⁵⁾	$ I_{PLF} \text{ SR}$	150	–	–		⁶⁾
Pull Level Keep Current ⁷⁾	$ I_{PLK} \text{ SR}$	–	–	10	μA	⁶⁾
Input high voltage (all except XTAL1)	$V_{IH} \text{ SR}$	$0.7 \times V_{DDP}$	–	$V_{DDP} + 0.3$	V	
Input low voltage (all except XTAL1)	$V_{IL} \text{ SR}$	-0.3	–	$0.3 \times V_{DDP}$	V	
Output High voltage ⁸⁾	$V_{OH} \text{ CC}$	$V_{DDP} - 1.0$	–	–	V	$I_{OH} \geq I_{OHmax}$
		$V_{DDP} - 0.4$	–	–	V	$I_{OH} \geq I_{OHnom}$ ⁹⁾

Electrical Parameters

- 2) The pad supply voltage pins (V_{DDPB}) provide the input current for the on-chip EVVRs and the current consumed by the pin output drivers. A small current is consumed because the drivers input stages are switched.
In Fast Startup Mode (with the Flash modules deactivated), the typical current is reduced to $3 + 0.6 \times f_{SYS}$.
- 3) Please consider the additional conditions described in section "Active Mode Power Supply Current".

Active Mode Power Supply Current

The actual power supply current in active mode not only depends on the system frequency but also on the configuration of the XC236xA's subsystem.

Besides the power consumed by the device logic the power supply pins also provide the current that flows through the pin output drivers.

A small current is consumed because the drivers' input stages are switched.

The IO power domains can be supplied separately. Power domain A (V_{DDPA}) supplies the A/D converters and Port 6. Power domain B (V_{DDPB}) supplies the on-chip EVVRs and all other ports.

During operation domain A draws a maximum current of 1.5 mA for each active A/D converter module from V_{DDPA} .

In Fast Startup Mode (with the Flash modules deactivated), the typical current is reduced to $(3 + 0.6 \times f_{SYS})$ mA.

Direct Drive

When direct drive operation is selected (SYSCON0.CLKSEL = 11_B), the system clock is derived directly from the input clock signal CLKIN1:

$$f_{\text{SYS}} = f_{\text{IN}}$$

The frequency of f_{SYS} is the same as the frequency of f_{IN} . In this case the high and low times of f_{SYS} are determined by the duty cycle of the input clock f_{IN} .

Selecting Bypass Operation from the XTAL1¹⁾ input and using a divider factor of 1 results in a similar configuration.

Prescaler Operation

When prescaler operation is selected (SYSCON0.CLKSEL = 10_B, PLLCON0.VCOBY = 1_B), the system clock is derived either from the crystal oscillator (input clock signal XTAL1) or from the internal clock source through the output prescaler K1 (= K1DIV+1):

$$f_{\text{SYS}} = f_{\text{OSC}} / K1.$$

If a divider factor of 1 is selected, the frequency of f_{SYS} equals the frequency of f_{OSC} . In this case the high and low times of f_{SYS} are determined by the duty cycle of the input clock f_{OSC} (external or internal).

The lowest system clock frequency results from selecting the maximum value for the divider factor K1:

$$f_{\text{SYS}} = f_{\text{OSC}} / 1024.$$

4.6.2.1 Phase Locked Loop (PLL)

When PLL operation is selected (SYSCON0.CLKSEL = 10_B, PLLCON0.VCOBY = 0_B), the on-chip phase locked loop is enabled and provides the system clock. The PLL multiplies the input frequency by the factor **F** ($f_{\text{SYS}} = f_{\text{IN}} \times \mathbf{F}$).

F is calculated from the input divider P (= PDIV+1), the multiplication factor N (= NDIV+1), and the output divider K2 (= K2DIV+1):

$$(\mathbf{F} = N / (P \times K2)).$$

The input clock can be derived either from an external source at XTAL1 or from the on-chip clock source.

The PLL circuit synchronizes the system clock to the input clock. This synchronization is performed smoothly so that the system clock frequency does not change abruptly.

Adjustment to the input clock continuously changes the frequency of f_{SYS} so that it is locked to f_{IN} . The slight variation causes a jitter of f_{SYS} which in turn affects the duration of individual TCSs.

1) Voltages on XTAL1 must comply to the core supply voltage V_{DDIM} .

PLL frequency band selection

Different frequency bands can be selected for the VCO so that the operation of the PLL can be adjusted to a wide range of input and output frequencies:

Table 24 System PLL Parameters

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
VCO output frequency (VCO controlled)	f_{VCO} CC	50	–	110	MHz	VCOSEL = 00 _B
		100	–	160	MHz	VCOSEL = 01 _B
VCO output frequency (VCO free-running)	f_{VCO} CC	10	–	40	MHz	VCOSEL = 00 _B
		20	–	80	MHz	VCOSEL = 01 _B

4.6.2.2 Wakeup Clock

When wakeup operation is selected (SYSCON0.CLKSEL = 00_B), the system clock is derived from the low-frequency wakeup clock source:

$$f_{SYS} = f_{WU}$$

In this mode, a basic functionality can be maintained without requiring an external clock source and while minimizing the power consumption.

4.6.2.3 Selecting and Changing the Operating Frequency

When selecting a clock source and the clock generation method, the required parameters must be carefully written to the respective bit fields, to avoid unintended intermediate states.

Many applications change the frequency of the system clock (f_{SYS}) during operation in order to optimize system performance and power consumption. Changing the operating frequency also changes the switching currents, which influences the power supply.

To ensure proper operation of the on-chip EVRs while they generate the core voltage, the operating frequency shall only be changed in certain steps. This prevents overshoots and undershoots of the supply voltage.

To avoid the indicated problems, recommended sequences are provided which ensure the intended operation of the clock system interacting with the power system.

Please refer to the Programmer's Guide.

Electrical Parameters

Table 26 is valid under the following conditions:

$V_{DDP} \geq 4.5 \text{ V}$; $V_{DDPtyp} = 5 \text{ V}$; $V_{DDP} \leq 5.5 \text{ V}$; $C_L \geq 20 \text{ pF}$; $C_L \leq 100 \text{ pF}$;

Table 26 Standard Pad Parameters for Upper Voltage Range

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Maximum output driver current (absolute value) ¹⁾	I_{Omax} CC	—	—	10	mA	Strong driver
		—	—	4.0	mA	Medium driver
		—	—	0.5	mA	Weak driver
Nominal output driver current (absolute value)	I_{Onom} CC	—	—	2.5	mA	Strong driver
		—	—	1.0	mA	Medium driver
		—	—	0.1	mA	Weak driver
Rise and Fall times (10% - 90%)	t_{RF} CC	—	—	$4.2 + 0.14 \times C_L$	ns	Strong driver; Sharp edge
		—	—	$11.6 + 0.22 \times C_L$	ns	Strong driver; Medium edge
		—	—	$20.6 + 0.22 \times C_L$	ns	Strong driver; Slow edge
		—	—	$23 + 0.6 \times C_L$	ns	Medium driver
		—	—	$212 + 1.9 \times C_L$	ns	Weak driver

1) The total output current that may be drawn at a given time must be limited to protect the supply rails from damage. For any group of 16 neighboring output pins, the total output current in each direction (ΣI_{OL} and ΣI_{OH}) must remain below 50 mA.

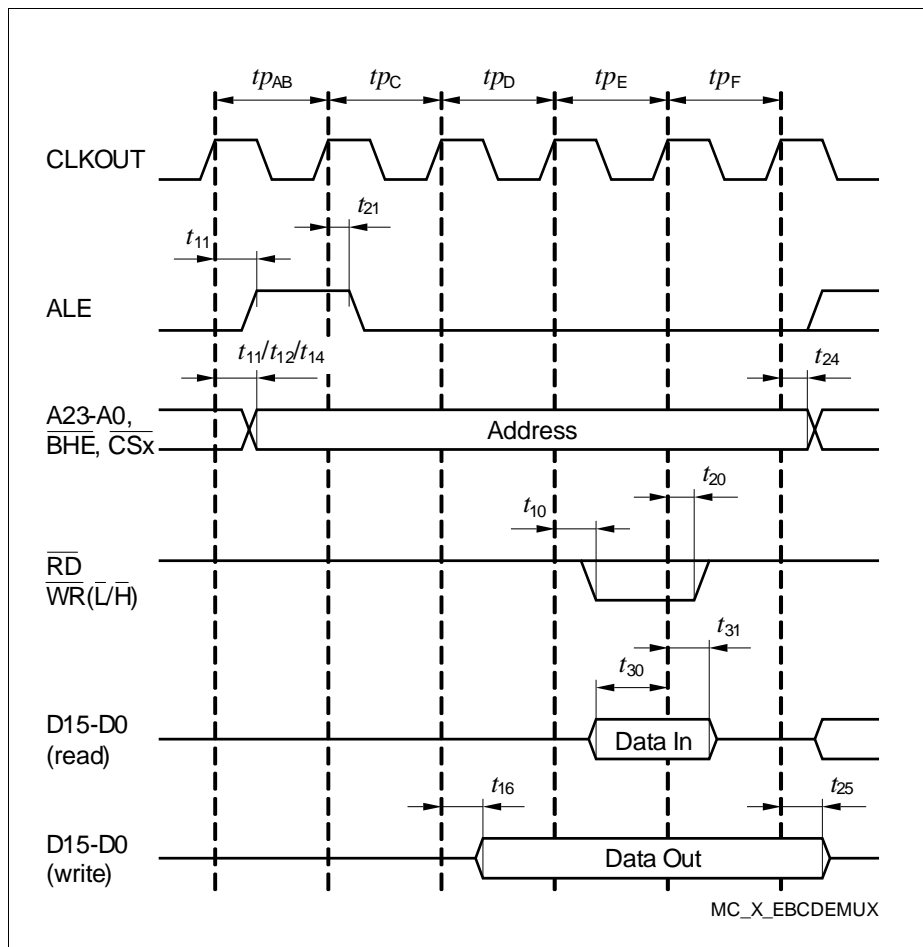


Figure 26 Demultiplexed Bus Cycle

Electrical Parameters

Table 33 USIC SSC Master Mode Timing for Lower Voltage Range (cont'd)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Receive data input setup time to SCLKOUT receive edge	t_4 SR	40	—	—	ns	
Data input DX0 hold time from SCLKOUT receive edge	t_5 SR	-5	—	—	ns	

1) $t_{SYS} = 1 / f_{SYS}$

Table 34 USIC SSC Slave Mode Timing for Upper Voltage Range

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Select input DX2 setup to first clock input DX1 transmit edge ¹⁾	t_{10} SR	7	—	—	ns	
Select input DX2 hold after last clock input DX1 receive edge ¹⁾	t_{11} SR	7	—	—	ns	
Receive data input setup time to shift clock receive edge ¹⁾	t_{12} SR	7	—	—	ns	
Data input DX0 hold time from clock input DX1 receive edge ¹⁾	t_{13} SR	5	—	—	ns	
Data output DOUT valid time	t_{14} CC	7	—	33	ns	

1) These input timings are valid for asynchronous input signal handling of slave select input, shift clock input, and receive data input (bits DXnCR.DSEN = 0).

Table 37 DAP Interface Timing for Lower Voltage Range

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
DAP0 clock period	t_{11} SR	25 ¹⁾	—	—	ns	
DAP0 high time	t_{12} SR	8	—	—	ns	
DAP0 low time	t_{13} SR	8	—	—	ns	
DAP0 clock rise time	t_{14} SR	—	—	4	ns	
DAP0 clock fall time	t_{15} SR	—	—	4	ns	
DAP1 setup to DAP0 rising edge	t_{16} SR	6	—	—	ns	pad_type= standard
DAP1 hold after DAP0 rising edge	t_{17} SR	6	—	—	ns	pad_type= standard
DAP1 valid per DAP0 clock period ²⁾	t_{19} CC	12	17	—	ns	pad_type= standard

1) The debug interface cannot operate faster than the overall system, therefore $t_{11} \geq t_{SYS}$.

2) The Host has to find a suitable sampling point by analyzing the sync telegram response.

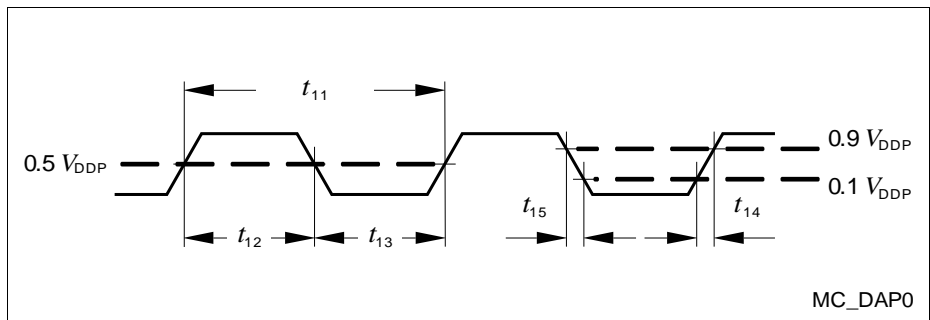


Figure 29 Test Clock Timing (DAP0)